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# **Microwave Imaging and Its Application**

Guest Editor:

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Deadline for manuscript submissions:

closed (30 September 2019)

### Message from the Guest Editor

The aim of this Special Issue is to collect contributions from scientists working in this field and in all the pertinent applicative contexts that provide recent advances in microwave imaging, including hardware design, image reconstruction methods, computational methods and experimental verification under realistic conditions.

Topics of interest for this Special Issue include, but are not limited to:

- Novel electromagnetic scattering models
- Linear and non-linear inversion methods and achievable performance
- Passive and/or non-cooperative source microwave imaging
- Information theoretic approaches for data selection and performance computation
- Numerically efficient inversion algorithms
- Hardware and antenna design
- Experimental in situ verification
- Antenna deconvolution and clutter rejection for near- and very nearzone configuration
- Phase only data microwave imaging

Please find more information here!

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### **Editor-in-Chief**

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## **Message from the Editor-in-Chief**

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